

**Search Notes**

Application/Control No.

10/584,102

Examiner

CHRIS C. CHU

Applicant(s)/Patent under  
Reexamination

SCHEUCHER, HEIMO

Art Unit

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	E21.524, E23.179, 797 & 48	2/18/2008	C.C.
257	238 & 68	2/18/2008	C.C.
257	620	2/18/2008	C.C.
430	22 & 5	2/18/2008	C.C.
430	311	2/18/2008	C.C.
324	633 & 765	2/18/2008	C.C.
324	754	2/18/2008	C.C.
356	399	2/18/2008	C.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; and IBM_TDB;	2/18/2008	C.C.